

| | | | |
|---|--|--|-------------------|
| PCN Number: | 20221216006.1 | PCN Date: | December 21, 2022 |
| Title: | Qualification of new Fab site (RFAB) using qualified Process Technology, Die Revision, and additional Assembly site/BOM options for select devices | | |
| Customer Contact: | PCN Manager | Dept: | Quality Services |
| Proposed 1st Ship Date: | Mar 21, 2023 | Sample Requests accepted until: | Jan 21, 2023 |

***Sample requests received after January 21, 2023 will not be supported.**

Change Type:

| | | | | | |
|-------------------------------------|-----------------|-------------------------------------|---------------------------|-------------------------------------|--------------------------|
| <input checked="" type="checkbox"/> | Assembly Site | <input checked="" type="checkbox"/> | Assembly Process | <input checked="" type="checkbox"/> | Assembly Materials |
| <input checked="" type="checkbox"/> | Design | <input type="checkbox"/> | Electrical Specification | <input type="checkbox"/> | Mechanical Specification |
| <input type="checkbox"/> | Test Site | <input checked="" type="checkbox"/> | Packing/Shipping/Labeling | <input type="checkbox"/> | Test Process |
| <input type="checkbox"/> | Wafer Bump Site | <input type="checkbox"/> | Wafer Bump Material | <input type="checkbox"/> | Wafer Bump Process |
| <input checked="" type="checkbox"/> | Wafer Fab Site | <input checked="" type="checkbox"/> | Wafer Fab Materials | <input checked="" type="checkbox"/> | Wafer Fab Process |
| | | <input type="checkbox"/> | Part number change | | |

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC9) die revision, and Assembly site/BOM options for selected devices as listed below in the product affected section.

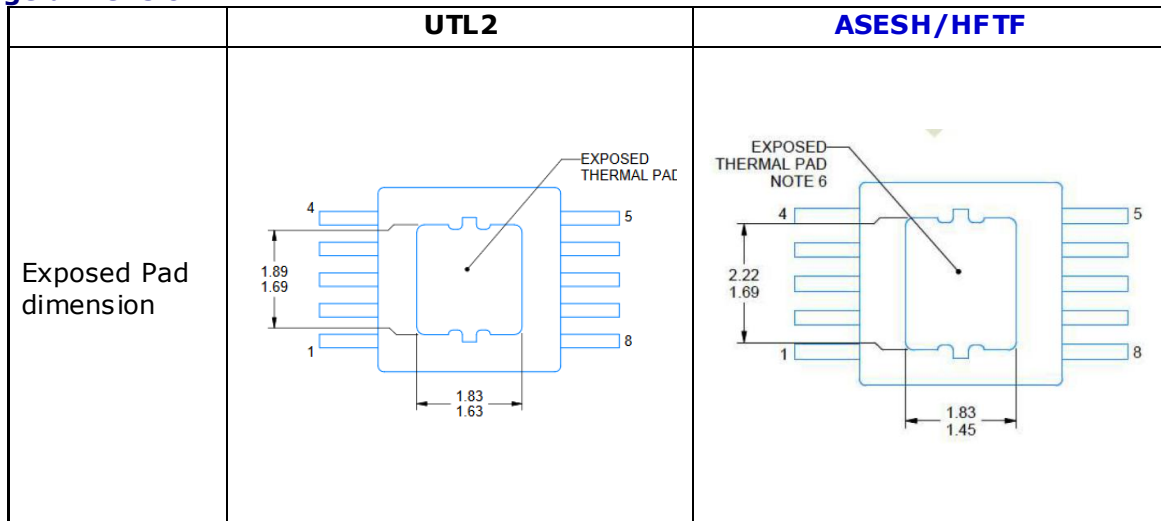
| Current Fab Site | | | Additional Fab Site | | |
|------------------|---------|----------------|---------------------|---------|----------------|
| Current Fab Site | Process | Wafer Diameter | Additional Fab Site | Process | Wafer Diameter |
| DL-LIN | LBC4 | 200 mm | RFAB | LBC9 | 300 mm |

The die was also changed as a result of the process change.

Construction differences between the Assembly sites are as follows:

| | UTL2 | ASESH | HFTF |
|----------------|--------|-----------|------|
| Mount Compound | PZ0013 | EY1000063 | A-24 |
| Mold Compound | CZ0094 | EN2000515 | R-32 |

Package dimension:



Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

| RoHS | REACH | Green Status | IEC 62474 |
|---|---|---|---|
| <input checked="" type="checkbox"/> No Change | <input checked="" type="checkbox"/> No Change | <input checked="" type="checkbox"/> No Change | <input checked="" type="checkbox"/> No Change |

Changes to product identification resulting from this PCN:

Fab Site Information:

| Chip Site | Chip Site Origin Code (20L) | Chip Site Country Code (21L) | Chip Site City |
|-------------|-----------------------------|------------------------------|-------------------|
| DL-LIN | DLN | USA | Dallas |
| RFAB | RFB | USA | Richardson |

Die Rev:

| Current | New |
|--------------|--------------|
| Die Rev [2P] | Die Rev [2P] |
| A | A |

| Assembly Site | Assembly Site Origin (22L) | Assembly Country Code (23L) | Assembly City |
|---------------|----------------------------|-----------------------------|--------------------------|
| UTL2 | NS2 | THA | Bangpakong, Chachoengsao |
| ASESH | ASH | CHN | Shanghai |
| HFTF | HFT | CHN | Hefei |

Sample product shipping label (not actual product label)

Product Affected:

| | |
|-------------|--------------|
| TPS40210DGQ | TPS40210DGQR |
|-------------|--------------|

For alternate parts with similar or improved performance, please visit the product page on TI.com

Qualification Report

Approved 29-Nov-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Type | # | Test Name | Test Name / Condition | Duration | Qual Device: TPS40210DGGQR | QBS Product Reference: TPS40210QDGGQRQ1 | QBS Product Reference: TPS40210QDGGQRQ1 | QBS Process Reference: TLC6C5816QPWPRQ1 | QBS Package Reference: TPS7B8250QDGNRQ1 |
|-------|----|-----------------------------|---|------------|-------------------------------|--|--|--|--|
| HAST | A2 | Biased HAST | 130C/85%RH | 96 Hours | - | 3/231/0 | 3/231/0 | 3/231/0 | 3/231/0 |
| UHAST | A3 | Unbiased HAST | 130C/85%RH | 96 Hours | - | 3/231/0 | 3/231/0 | 3/231/0 | - |
| TC | A4 | Temperature Cycle | -65/150C | 500 Cycles | - | 3/231/0 | 3/231/0 | 3/231/0 | 3/231/0 |
| HTSL | A6 | High Temp. Storage Bake | 170C | 420 Hours | - | 3/135/0 | 3/135/0 | 3/231/0 | 3/135/0 |
| HTOL | B1 | Life Test | 125C | 1000 Hours | - | - | 1/77/0 | 2/154/0 | - |
| ELFR | B2 | Early Life Failure Rate | 150C | 48 Hours | - | - | - | 3/2400/0 | - |
| SD | C3 | Solderability | Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder.) | Pb | - | - | 1/15/0 | - | - |
| SD | C3 | PB-Free Solderability | Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-free Solder.) | Pb-Free | - | - | 1/15/0 | - | - |
| PD | C4 | Physical Dimensions | (per mechanical drawing) | -- | - | - | 3/30/0 | - | 3/30/0 |
| HBM | E2 | ESD - HBM | - | 3000 V | - | - | 1/3/0 | 1/3/0 | 1/3/0 |
| CDM | E3 | ESD - CDM | - | 1000 V | - | - | 1/3/0 | 1/3/0 | 1/3/0 |
| LU | E4 | Latch-up | Per JESD78 | - | - | - | 1/6/0 | 1/6/0 | 1/6/0 |
| CHAR | E5 | Electrical characterization | Per Datasheet Parameter | - | - | - | 3/60/0 | 3/60/0 | 3/60/0 |

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green TI

Qualification Report

Approved 29-Nov-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Type | # | Test Name | Test Name / Condition | Duration | Qual Device: TPS40210DGGQR | QBS Product Reference: TPS40210QDGGQRQ1 | QBS Product Reference: TPS40210QDGGQRQ1 | QBS Process Reference: TLC6C5816QPWPRQ1 | QBS Package Reference: TCA39306DCURQ1 |
|-------|----|-----------------------------|---|------------|-------------------------------|--|--|--|--|
| HAST | A2 | Biased HAST | 130C/85%RH | 96 Hours | - | 3/231/0 | 3/231/0 | 3/231/0 | |
| UHAST | A3 | Unbiased HAST | 130C/85%RH | 96 Hours | - | 3/231/0 | 3/231/0 | 3/231/0 | |
| TC | A4 | Temperature Cycle | -65/150C | 500 Cycles | - | 3/231/0 | 3/231/0 | 3/231/0 | |
| HTSL | A6 | High Temp. Storage Bake | 170C | 420 Hours | - | - | 3/135/0 | 3/231/0 | |
| HTOL | B1 | Life Test | 125C | 1000 Hours | - | - | 1/77/0 | 2/154/0 | |
| ELFR | B2 | Early Life Failure Rate | 150C | 48 Hours | - | - | - | 3/2400/0 | |
| SD | C3 | Solderability | Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder.) | Pb | - | - | 1/15/0 | - | |
| SD | C3 | PB-Free Solderability | Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-free Solder.) | Pb-Free | - | - | 1/15/0 | - | |
| PD | C4 | Physical Dimensions | (per mechanical drawing) | -- | - | - | 3/30/0 | - | |
| HBM | E2 | ESD - HBM | - | 3000 V | - | - | 1/3/0 | 1/3/0 | |
| CDM | E3 | ESD - CDM | - | 1000 V | - | - | 1/3/0 | 1/3/0 | |
| LU | E4 | Latch-up | Per JESD78 | - | - | - | 1/6/0 | 1/6/0 | |
| CHAR | E5 | Electrical characterization | Per Datasheet Parameter | - | - | - | 3/60/0 | 3/60/0 | |

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
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Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green TI

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

| Location | E-Mail |
|---------------------------|--|
| WW Change Management Team | PCN_ww_admin_team@list.ti.com |

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